

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/696,151	CHENG ET AL.
	<b>Examiner</b> Matthew Landau	<b>Art Unit</b> 2815

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
257	301, 302, E27.091-	4/22/08	ML
	E27.093	d.	